



Product Change Notification: JAON-26MATN756

Date:

31-Oct-2024

Product Category:

8-Bit Microcontrollers, Analog Temperature Sensors, Capacitive Touch Sensors, Digital Temperature Sensors, Linear Op Amps, Memory

Notification Subject:

CCB 5297 and 5297.001 Final Notice: Qualification of palladium coated copper with gold flash (CuPdAu) as a new bond wire material and 8006NS as a new die attach material for selected 24AA0x, 24C01C, 24LC0x, 24VL0x, 25AA0x, 25LC0x, 34AA02, 34LC02, 34VL02, 93AAx, 93C46x, 93C56x, 93C66x, 93C76x, 93C86x, 93LCx, MCP64x, MCP6V1x, MCP6V3x, MCP6V6x, MCP6V7x, MCP6V8x, MCP6V9x, MCP9x, MTCH101, PIC10F20x, PIC10F22x, device families available in 6L and 5L SOT-23 packages assembled at MMT assembly site.

Affected CPNs:

[JAON-26MATN756_Affected_CPN_10312024.pdf](#)

[JAON-26MATN756_Affected_CPN_10312024.csv](#)

PCN Status: Final Notification

PCN Type: Manufacturing Change

Microchip Parts Affected: Please open one of the files found in the Affected CPNs section.

Note: For your convenience Microchip includes identical files in two formats (.pdf and .xls)

Description of Change: Qualification of palladium coated copper with gold flash (CuPdAu) as a new bond wire material and 8006NS as a new die attach material for selected 24AA0x, 24C01C, 24LC0x, 24VL0x, 25AA0x, 25LC0x, 34AA02, 34LC02, 34VL02, 93AAx, 93C46x, 93C56x, 93C66x, 93C76x, 93C86x, 93LCx, MCP64x, MCP6V1x, MCP6V3x, MCP6V6x, MCP6V7x, MCP6V8x, MCP6V9x, MCP9x, MTCH101, PIC10F20x, PIC10F22x, device families available in 6L and 5L SOT-23 packages assembled at MMT assembly site.

Pre and Post Summary Changes:

Qual Report Availability							X							
Final PCN Issue Date							X							
Estimated Implementation Date											X			

Method to Identify Change: Traceability Code

Qualification Report: Please open the attachments included with this PCN labeled as PCN_#_Qual_Report.

Revision History: September 28, 2022: Issued initial notification.

November 05, 2024: Issued final notification. Attached the Qualification Report. Updated the affected parts list base on the updated scope. Updated the die attach material in the pre and post change from 8900NC to 8006NS based on the revised form. Provided estimated first ship date to be on December 05, 2024.

Note: The change described in this PCN does not alter Microchip's current regulatory compliance regarding the material content of the applicable product.

Attachments:

PCN_JAON-26MATN756_Qualification Report.pdf

Please contact your local **Microchip sales office** with questions or concerns regarding this notification.

Terms and Conditions:

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MCP6V91UT-E/OT
MCP6V96T-E/OT
MCP6V96UT-E/OT
93LC46AT-I/OT
93AA46AT-I/OT
93AA46AE48T-I/OT
93LC46AT-E/OT
93LC46BT-I/OT
93AA46BT-I/OT
93LC46BT-E/OT
93C46BT-I/OT
93C46BT-E/OT
93C46AT-I/OT
93C46AT-E/OT
93LC56AT-I/OT
93AA56AT-I/OT
93LC56BT-I/OT
93AA56BT-I/OT
93LC56AT-E/OT
93LC56BT-E/OT
93LC66AT-I/OT
93AA66AT-I/OT
93LC66BT-I/OT
93AA66BT-I/OT
93LC66AT-E/OT
93LC66BT-E/OT
93C56AT-I/OT
93C56BT-I/OT
93C56AT-E/OT
93C56BT-E/OT
93C66AT-I/OT
93C66BT-I/OT
93C66AT-E/OT
93C66BT-E/OT
93LC76AT-I/OT
93AA76AT-I/OT
93LC76BT-I/OT
93AA76BT-I/OT
93LC76AT-E/OT
93LC76BT-E/OT
93LC86AT-I/OT
93AA86AT-I/OT
93LC86BT-I/OT
93AA86BT-I/OT
93LC86AT-E/OT
93LC86BT-E/OT

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93C76AT-E/OT
93C76BT-E/OT
93C86AT-I/OT
93C86BT-I/OT
93C86AT-E/OT
93C86BT-E/OT
25LC010AT-I/OT
25AA010AT-I/OT
25LC010AT-E/OT
25LC020AT-I/OT
25AA020AT-I/OT
25AA02E48T-I/OT
25AA02E64T-I/OT
25AA02UIDT-I/OT
25LC020AT-E/OT
25LC040AT-I/OT
25AA040AT-I/OT
25LC040AT-E/OT
24VL025T/OT
24LC025T-I/OT
24AA025T-I/OT
24LC025T-E/OT
24VL014T/OT
24LC014T-I/OT
24AA014T-I/OT
24LC014T-E/OT
24C01CT-I/OT
24C01CT-E/OT
24AA025E48T-I/OT
24AA025E64T-I/OT
24AA025UIDT-I/OT
24AA025E48T-E/OT
24AA025E64T-E/OT
34VL02T/OT
34LC02T-I/OT
34AA02T-I/OT
34LC02T-E/OT
34AA02T-E/OT
PIC10F200-E/OT
PIC10F200-I/OT215
PIC10F200-I/OT220
PIC10F200-I/OT223
PIC10F200-I/OT
PIC10F200T-I/OT071
PIC10F200T-I/OT102
PIC10F200T-I/OT108
PIC10F200T-I/OT119

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PIC10F200T-I/OT131
PIC10F200T-I/OT151
PIC10F200T-I/OT153
PIC10F200T-I/OT163
PIC10F200T-I/OT169
PIC10F200T-I/OT177
PIC10F200T-I/OT182
PIC10F200T-I/OT185
PIC10F200T-I/OT190
PIC10F200T-I/OT192
PIC10F200T-I/OT194
PIC10F200T-I/OT195
PIC10F200T-I/OT196
PIC10F200T-I/OT200
PIC10F200T-I/OT202
PIC10F200T-I/OT208
PIC10F200T-I/OT209
PIC10F200T-I/OT212
PIC10F200T-I/OT215
PIC10F200T-I/OT216
PIC10F200T-I/OT217
PIC10F200T-I/OT219
PIC10F200T-I/OT220
PIC10F200T-I/OT221
PIC10F200T-I/OT222
PIC10F200T-I/OT223
PIC10F200T-I/OT224
PIC10F200T-I/OT225
PIC10F200T-I/OT226
PIC10F200T-I/OT227
PIC10F200T-I/OT228
PIC10F200T-I/OT
PIC10F200T-E/OT030
PIC10F200T-E/OT147
PIC10F200T-E/OT186
PIC10F200T-E/OT191
PIC10F200T-E/OT198
PIC10F200T-E/OT
PIC10F202-E/OT
PIC10F202-I/OT
PIC10F202T-I/OT065
PIC10F202T-I/OT085
PIC10F202T-I/OT105
PIC10F202T-I/OT108
PIC10F202T-I/OT112
PIC10F202T-I/OT
PIC10F202T-E/OT081

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PIC10F202T-E/OT
PIC10F204-E/OT
PIC10F204-I/OT
PIC10F204T-I/OT043
PIC10F204T-I/OT051
PIC10F204T-I/OT053
PIC10F204T-I/OT054
PIC10F204T-I/OT
PIC10F204T-E/OT028
PIC10F204T-E/OT038
PIC10F204T-E/OT050
PIC10F204T-E/OT
PIC10F206-E/OT
PIC10F206-I/OT
PIC10F206T-I/OT030
PIC10F206T-I/OT031
PIC10F206T-I/OT032
PIC10F206T-I/OT041
PIC10F206T-I/OT043
PIC10F206T-I/OT
PIC10F206T-E/OT
PIC10F220-E/OT043
PIC10F220-E/OT
PIC10F220-I/OT
PIC10F220T-I/OT024
PIC10F220T-I/OT027
PIC10F220T-I/OT035
PIC10F220T-I/OT037
PIC10F220T-I/OT040
PIC10F220T-I/OT
PIC10F220T-E/OT030
PIC10F220T-E/OT
PIC10F222-E/OT
MTCH101-I/OT
PIC10F222-I/OT
PIC10F222T-I/OT020
PIC10F222T-I/OT032
PIC10F222T-I/OT033
PIC10F222T-I/OT039
PIC10F222T-I/OT044
PIC10F222T-I/OT045
MTCH101T-I/OT
PIC10F222T-I/OT053
PIC10F222T-I/OT055
PIC10F222T-I/OT056
PIC10F222T-I/OT057
PIC10F222T-I/OT058

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PIC10F222T-I/OT

PIC10F222T-E/OT

MCP9509HT-E/OTBAB

MCP6V11T-E/OT

MCP6V11UT-E/OT

MCP6V16T-E/OT

MCP6V16UT-E/OT

MCP6V31T-E/OT

MCP6V31UT-E/OT

MCP6V36T-E/OT

MCP6V36UT-E/OT

MCP9802A0T-M/OT

MCP6471T-E/OT

MCP6481T-E/OT

MCP6491T-E/OT

MCP6421T-E/OT

MCP6V61T-E/OT

MCP6V61UT-E/OT

MCP6V66T-E/OT

MCP6V66UT-E/OT

MCP6V71T-E/OT

MCP6V71UT-E/OT

MCP6V76T-E/OT

MCP6V76UT-E/OT

MCP6V81T-E/OT

MCP6V81UT-E/OT

MCP6V86T-E/OT

MCP6V86UT-E/OT

MCP6V91T-E/OT



QUALIFICATION REPORT SUMMARY

RELIABILITY LABORATORY

PCN #: JAON-26MATN756

Date:
September 5, 2024

Qualification of palladium coated copper with gold flash (CuPdAu) as a new bond wire material and 8006NS as a new die attach material for selected 24AA0x, 24C01C, 24LC0x, 24VL0x, 25AA0x, 25LC0x, 34AA02, 34LC02, 34VL02, 93AAx, 93C46x, 93C56x, 93C66x, 93C76x, 93C86x, 93LCx, MCP64x, MCP6V1x, MCP6V3x, MCP6V6x, MCP6V7x, MCP6V8x, MCP6V9x, MCP9x, MTCH101, PIC10F20x, PIC10F22x, device families available in 6L and 5L SOT-23 packages assembled at MMT assembly site.



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PACKAGE QUALIFICATION REPORT

Purpose Qualification of palladium coated copper with gold flash (CuPdAu) as a new bond wire material and 8006NS as a new die attach material for selected 24AA0x, 24C01C, 24LC0x, 24VL0x, 25AA0x, 25LC0x, 34AA02, 34LC02, 34VL02, 93AAx, 93C46x, 93C56x, 93C66x, 93C76x, 93C86x, 93LCx, MCP64x, MCP6V1x, MCP6V3x, MCP6V6x, MCP6V7x, MCP6V8x, MCP6V9x, MCP9x, MTCH101, PIC10F20x, PIC10F22x, device families available in 6L and 5L SOT-23 packages assembled at MMT assembly site.

CCB No. 5297 and 5297.001
CN E000210478
QUAL ID R2400824 Rev. A
MP CODE DECA14C8XAXF
Part No. PIC10F220-E/OT
Bonding No. BD-002055 Rev. 01

Package

Type 6L SOT-23

Lead Frame

Paddle size 72 x 41mils
Material CDA194
Surface Ag Ring Plated
Process Stamped
Lead Lock No
Part Number 10100607
Treatment BOT

Material

Epoxy 8006NS
Wire CuPdAu wire
Mold Compound G600V
Plating Composition Matte Sn



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PACKAGE QUALIFICATION REPORT

Manufacturing Information:

Assembly Lot No.	Wafer Lot No.	Date Code
MMT-250401685.000	TMPE224169414.300	2417A6U (Top Mark: A06U)
MMT-250401686.000	TMPE224169414.300	2417A6V (Top Mark: A06V)
MMT-250401687.000	TMPE224169414.300	2417A7R (Top Mark: A07R)

Result

☒ Pass ☐ Fail ☐ _____

6L SOT-23 assembled by MMT pass reliability test per QCI-39000.
This package was qualified the Moisture/Reflow Sensitivity Classification Level 1
at 260°C reflow temperature per IPC/JEDEC J-STD-020E standard.

PACKAGE QUALIFICATION REPORT

Test Number (Reference)	Test Condition	Standard/ Method	Qty. (Acc.)	Def/SS	Result	Remarks
<u>Precondition</u> <u>Prior Perform</u> <u>Reliability Tests</u> (At MSL Level 1)	Electrical Test: +25°C and 125°C System: J750	JESD22-A113	693(0)	0/693		Good Devices
	Bake 150°C, 24 hrs.	JIP/		693		
	System: CHINEE	IPC/JEDEC		693		
	85°C/85%RH Moisture Soak 168 hrs.	J-STD-020E		693		
	System: TABAI ESPEC Model PR-3SPH			693		
	3x Convection-Reflow 265°C max					
	System: Vitronics Soltec MR1243					
	Electrical Test: +25°C and 125°C System: J750		693(0)	0/693	Pass	

PACKAGE QUALIFICATION REPORT

Test Number (Reference)	Test Condition	Standard/ Method	Qty. (Acc.)	Def/SS.	Result	Remarks
Temp Cycle	Stress Condition: -65°C to +150°C, 500 Cycles System: TABAI ESPEC TSA-70H Electrical Test: + 125°C System: J750 Bond Strength: Wire Pull (>2.50 grams)	JESD22-A104		0/231		Parts had been pre-conditioned at 260°C 77 units / lot
			231(0)	0/231	Pass	
			15(0)	0/15	Pass	
			15(0)	0/15	Pass	
UNBIASED-HAST	Stress Condition: +130°C/85%RH, 96 hrs. System: HAST 6000X Electrical Test: +25°C System: J750	JESD22-A118		0/231		Parts had been pre-conditioned at 260°C
			231(0)	0/231	Pass	77 units / lot
HAST	Stress Condition: +130°C/85%RH, 96 hrs. Bias Volt: 5.5 Volts System: HAST 6000X Electrical Test: +25°C and 125°C System: J750	JESD22-A110		0/231		Parts had been pre-conditioned at 260°C
			231(0)	0/231	Pass	77 units / lot

PACKAGE QUALIFICATION REPORT

Test Number (Reference)	Test Condition	Standard/ Method	Qty. (Acc.)	Def/SS.	Result	Remarks
High Temperature Storage Life	Stress Condition: Bake 175°C, 504 hrs System: CHINEE, TPS Bake Oven	JESD22- A103		0/45		45 units
	Electrical Test: +25°C and 125°C System: J750		45(0)	0/45	Pass	
Bond Line Thickness	Bond Line Thickness	SPI-45528	15(0)	15(0)	Pass	5 units / lot
Wire sweep	Wire sweep Inspection 15 Wires / lot	-	45(0) Wires	0/45	Pass	
Bond Strength Data Assembly	Wire Pull (>2.50 grams)	Mil. Std. 883-2011	30(0) Wires	0/30	Pass	
	Bond Shear (>15.00 grams)	CDF-AEC- Q100-001	30(0) bonds	0/30	Pass	